International Rectifier

IRF7101PbF

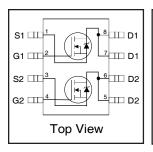
- Adavanced Process Technology
- Ultra Low On-Resistance
- Dual N-Channel MOSFET
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching
- Lead-Free

Description

Fourth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and dual-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.

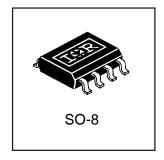
HEXFET® Power MOSFET



$$V_{DSS} = 20V$$

$$R_{DS(on)} = 0.10\Omega$$

$$I_D = 3.5A$$



Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	3.5		
I _D @ T _A = 100°C Continuous Drain Current, V _{GS} @ 10V		2.3	Α	
I _{DM}	Pulsed Drain Current ①	14		
P _D @T _C = 25°C	Power Dissipation	2.0	W	
	Linear Derating Factor	0.016	W/°C	
V _{GS}	Gate-to-Source Voltage	± 12	V	
dv/dt	Peak Diode Recovery dv/dt ②	3.0	V/nS	
T _{J,} T _{STG}	Junction and Storage Temperature Range	-55 to + 150		
	Sodering Temperature, for 10 seconds	300(1.6mm from case)	℃	

Thermal Resistance Ratings

	Parameter	Min.	Тур.	Max	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ④			62.5	°C/W

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	20			V	$V_{GS} = 0V, I_{D} = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.025		V/°C	Reference to 25°C, I _D = 1mA
Static Drain to Source On Resistance			0.10	0	V _{GS} = 10V, I _D = 1.8A ③
Static Diamin-to-Source On-Tresistance			0.15	52	V _{GS} = 4.5V, I _D = 1.0A ③
Gate Threshold Voltage	1.0		3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Forward Transconductance	1.1			S	V _{DS} = 15V, I _D = 3.5A ③
Dunin to Course Leakers Comment			2.0		$V_{DS} = 20V, V_{GS} = 0V$
Dialii-to-Source Leakage Current			250	μΑ	V _{DS} = 16V, V _{GS} = 0V, T _J = 125 °C
Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 12V
Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = - 12V
Total Gate Charge			15		I _D = 1.8A
Gate-to-Source Charge			2.0	nC	V _{DS} = 16V
Gate-to-Drain ("Miller") Charge			3.6		V _{GS} = 10V
Turn-On Delay Time		7.0			V _{DD} = 10V
Rise Time		10			I _D = 1.8A
Turn-Off Delay Time		24		ns	$R_G = 8.2\Omega$
Fall Time		30			$R_D = 26\Omega$
Internal Drain Inductance		4.0		nН	Between lead,6mm(0.25in.)
Internal Source Inductance		6.0	_		from package and center of die contact
Input Capacitance		320			V _{GS} = 0V
Output Capacitance		250		pF	V _{DS} = 15V
Reverse Transfer Capacitance		75			f = 1.0MHz
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Utput Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance 1.1 Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 20 — Breakdown Voltage Temp. Coefficient — 0.025 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage 1.0 — Forward Transconductance 1.1 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 7.0 Rise Time — 10 Turn-Off Delay Time — 24 Fall Time — 30 Internal Drain Inductance — 4.0 Internal Source Inductance — 6.0 Input Capacitance — 250	Drain-to-Source Breakdown Voltage 20 —— —— Breakdown Voltage Temp. Coefficient —— 0.025 —— Static Drain-to-Source On-Resistance —— 0.10 Gate Threshold Voltage 1.0 —— 3.0 Forward Transconductance 1.1 —— —— Drain-to-Source Leakage Current —— 2.0 —— 250 Gate-to-Source Forward Leakage —— 100 —— 250 Gate-to-Source Reverse Leakage —— -100 —— 15 Gate-to-Source Charge —— -100 — 3.6 Turn-On Delay Time —— 2.0 — — -100 — Rise Time — 7.0 — — Rise Time — 10 — Turn-Off Delay Time — 24 — Fall Time — 4.0 — Internal Drain Inductance — 4.0 — — Internal Source Inductance — - 250 — <td>Drain-to-Source Breakdown Voltage 20 — — V Breakdown Voltage Temp. Coefficient — 0.025 — V/°C Static Drain-to-Source On-Resistance — — 0.10 Ω Gate Threshold Voltage 1.0 — 3.0 V Forward Transconductance 1.1 — — S Drain-to-Source Leakage Current — — 2.0 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 15 nC Gate-to-Source Charge — — 15 nC Gate-to-Drain ("Miller") Charge — — 3.6 Turn-On Delay Time — 7.0 — Rise Time — 10 — Turn-Off Delay Time — 24 — Fall Time — 30 — Intern</td>	Drain-to-Source Breakdown Voltage 20 — — V Breakdown Voltage Temp. Coefficient — 0.025 — V/°C Static Drain-to-Source On-Resistance — — 0.10 Ω Gate Threshold Voltage 1.0 — 3.0 V Forward Transconductance 1.1 — — S Drain-to-Source Leakage Current — — 2.0 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 15 nC Gate-to-Source Charge — — 15 nC Gate-to-Drain ("Miller") Charge — — 3.6 Turn-On Delay Time — 7.0 — Rise Time — 10 — Turn-Off Delay Time — 24 — Fall Time — 30 — Intern

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
ls	Continuous Source Current			2.0		MOSFET symbol
	(Body Diode)			_ 2.0	Α	showing the
I _{SM}	Pulsed Source Current			14	A	integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.2	V	$T_J = 25$ °C, $I_S = 1.7A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		36	54	ns	$T_J = 25$ °C, $I_F = 1.7A$
Q _{rr}	Reverse RecoveryCharge		41	62	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intr	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- $\begin{tabular}{ll} @ & I_{SD} \leq 3.5A, & di/dt \leq 90A/\mu s, & V_{DD} \leq V_{(BR)DSS}, \\ & T_{J} \leq 150 ^{\circ} C \end{tabular}$
- 4 Surface mounted on FR-4 board, $t \leq 10$ sec.

IRF7101PbF

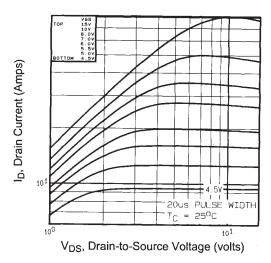


Fig 1. Typical Output Characteristics,

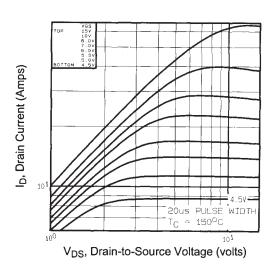


Fig 2. Typical Output Characteristics,

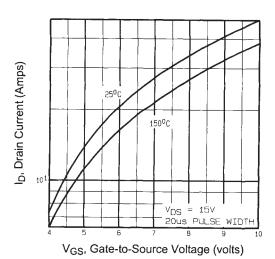


Fig 3. Typical Transfer Characteristics

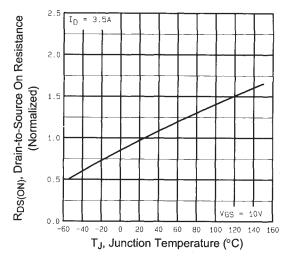


Fig 4. Normalized On-Resistance Vs. Temperature

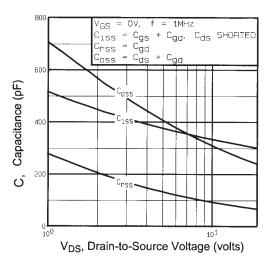


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

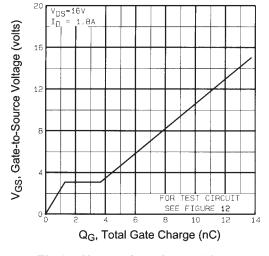


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

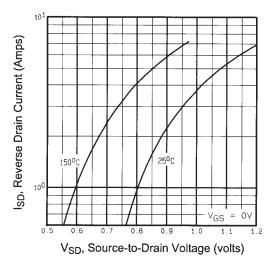


Fig 7. Typical Source-Drain Diode Forward Voltage

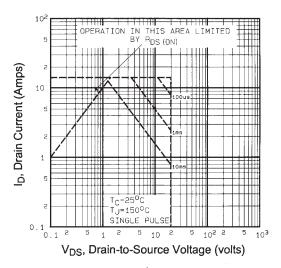


Fig 8. Maximum Safe Operating Area

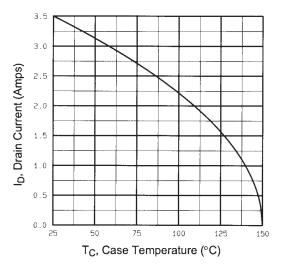


Fig 9. Maximum Drain Current Vs. Case Temperature

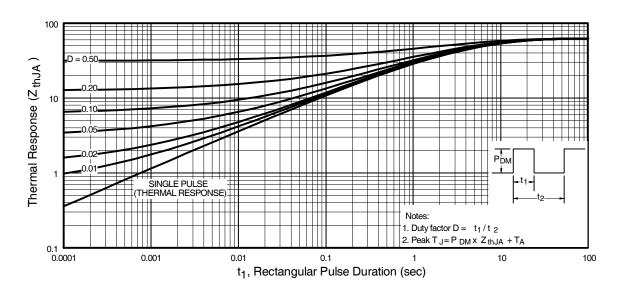


Fig 10. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

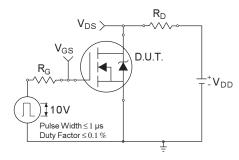


Fig 11a. Switching Time Test Circuit

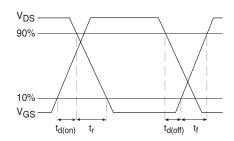


Fig 11b. Switching Time Waveforms

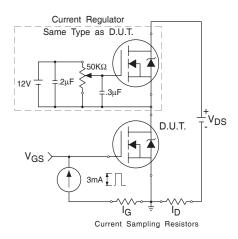


Fig 12a. Gate Charge Test Circuit

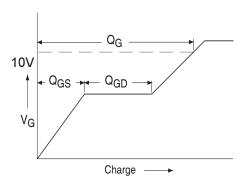
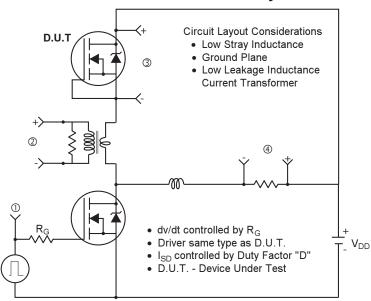


Fig 12b. Basic Gate Charge Waveform

Peak Diode Recovery dv/dt Test Circuit



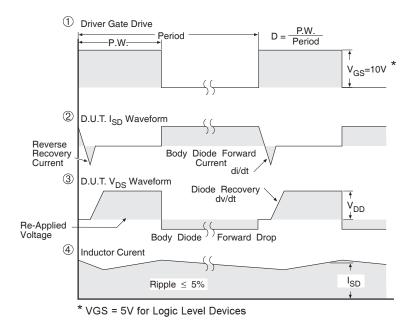
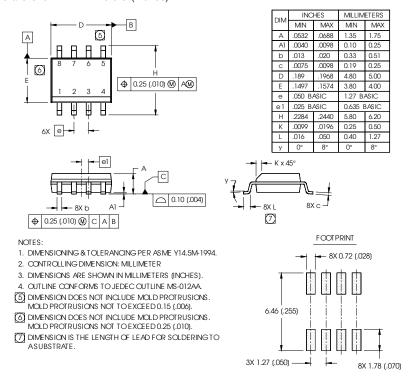


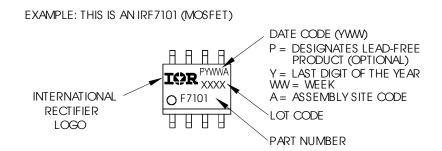
Fig 13. For N-Channel HEXFETS

SO-8 Package Outline

Dimensions are shown in milimeters (inches)

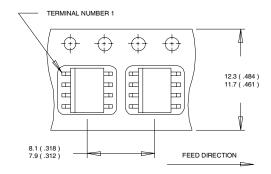


SO-8 Part Marking Information (Lead-Free)



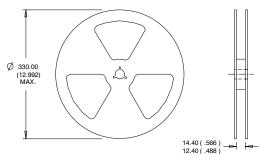
SO-8 Tape and Reel

Dimensions are shown in milimeters (inches)



NOTES

- 1. CONTROLLING DIMENSION: MILLIMETER.
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES:
 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualifications Standards can be found on IR's Web site.



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